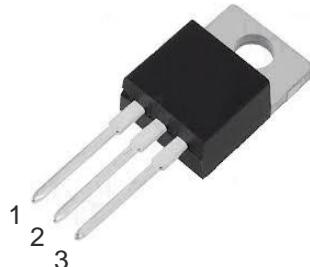


650V / 4A N-Channel Enhancement Mode MOSFET	650V, $R_{DS(ON)}=2.8\Omega$ @ $V_{GS}=10V$, $I_D=2A$
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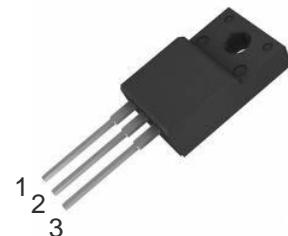
Features

- Low On-State Resistance
- Fast Switching
- Low Gate Charge & Low C_{RSS}
- Fully Characterized Avalanche Voltage and Current
- Specially Designed for AC Adapter, Battery Charger and SMPS
- In compliance with EU RoHS 2002/95/EC Directives

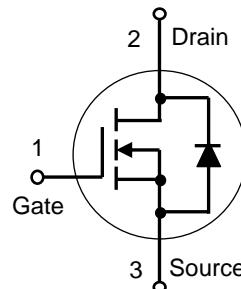
TO-220AB



ITO-220AB

**Mechanical Information**

- Case: TO-220AB / ITO-220AB Molded Plastic
- Terminals : Solderable per MIL-STD-750,Method 2026

**Marking & Ordering Information**

TYPE	MARKING	PACKAGE	PACKING
HY4N65T	4N65T	TO-220AB	50PCS/TUBE
HY4N65FT	4N65FT	ITO-220AB	50PCS/TUBE

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise specified)

Parameter	Symbol	HY4N65T	HY4N65FT	Units
Drain-Source Voltage	V_{DS}	650		V
Gate-Source Voltage	V_{GS}	± 30		V
Continuous Drain Current	I_D	4	4	A
Pulsed Drain Current ¹⁾	I_{DM}	16	16	A
Maximum Power Dissipation Derating Factor	P_D	71 0.57	26 0.21	W
Avalanche Energy with Single Pulse $I_{AS}=4A$, $V_{DD}=150V$, $L=22.5mH$	E_{AS}	180		mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 to +150		°C

Note : 1. Maximum DC current limited by the package

Thermal Characteristics

Parameter	Symbol	HY4N65T	HY4N65FT	Units
Junction-to-Case Thermal Resistance	$R_{\theta JC}$	1.76	4.8	°C/W
Junction-to-Case Thermal Resistance	$R_{\theta JA}$	50	110	°C/W

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Electrical Characteristics ($T_C=25^\circ\text{C}$, Unless otherwise noted)

Paramter	Symbol	Test Condition	Min.	Typ.	Max.	Units
Static						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V} \cdot I_{\text{D}}=250\mu\text{A}$	650	-	-	V
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{DS}}=V_{\text{GS}} \cdot I_{\text{D}}=250\mu\text{A}$	2.0	-	4.0	V
Drain-Source On-State Resistance	$R_{\text{DS(ON)}}$	$V_{\text{GS}}=10\text{V} \cdot I_{\text{D}}=2\text{A}$	-	2.5	2.8	Ω
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=650\text{V} \cdot V_{\text{GS}}=0\text{V}$	-	-	10	μA
Gate Body Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 30\text{V} \cdot V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Dynamic						
Total Gate Charge	Q_g	$V_{\text{DS}}=520\text{V} \cdot I_{\text{D}}=4\text{A}$ $V_{\text{GS}}=10\text{V}$	-	16.2	20	nC
Gate-Source Charge	Q_{gs}		-	3.2	-	
Gate-Drain Charge	Q_{gd}		-	5.6	-	
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}}=325\text{V} \cdot I_{\text{D}}=4\text{A}$ $V_{\text{GS}}=10\text{V} \cdot R_{\text{G}}=25\Omega$	-	16.8	22	ns
Turn-On Rise Time	t_r		-	36	46	
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	21.8	32	
Turn-Off Fall Time	t_f		-	19.2	28	
Input Capacitance	C_{iss}	$V_{\text{DS}}=25\text{V} \cdot V_{\text{GS}}=0\text{V}$ $f=1.0\text{MHz}$	-	480	-	pF
Output Capacitance	C_{oss}		-	65	-	
Reverse Transfer Capacitance	C_{rss}		-	1.3	-	
Source-Drain Diode						
Max. Diode Forward Voltage	I_s	-	-	-	4.0	A
Max. Pulsed Source Current	I_{SM}	-	-	-	16.0	A
Diode Forward Voltage	V_{SD}	$I_s=4\text{A} \cdot V_{\text{GS}}=0\text{V}$	-	-	1.4	V
Reverse Recovery Time	t_{rr}	$V_{\text{GS}}=0\text{V} \cdot I_s=4\text{A}$ $di/dt=100\text{A/us}$	-	210	-	ns
Reverse Recovery Charge	Q_{rr}		-	0.8	-	uC

NOTE : Pulse Test : Pulse Width $\leq 300\text{us}$, duty cycle $\leq 2\%$

Typical Characteristics Curves ($T_C=25^\circ\text{C}$, unless otherwise noted)

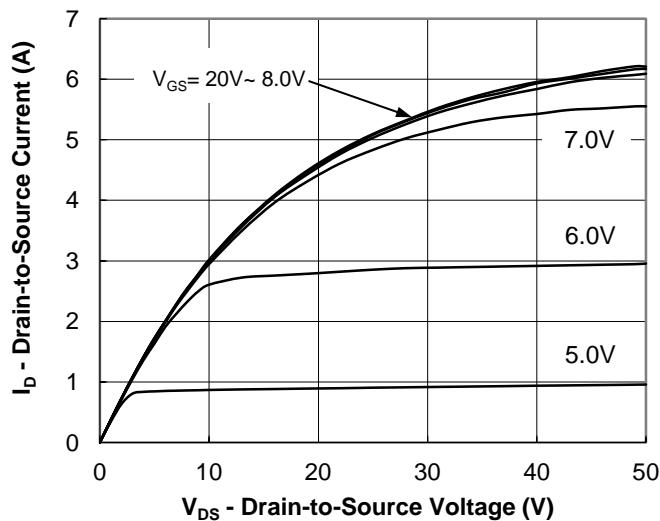


Fig.1 Output Characteristic

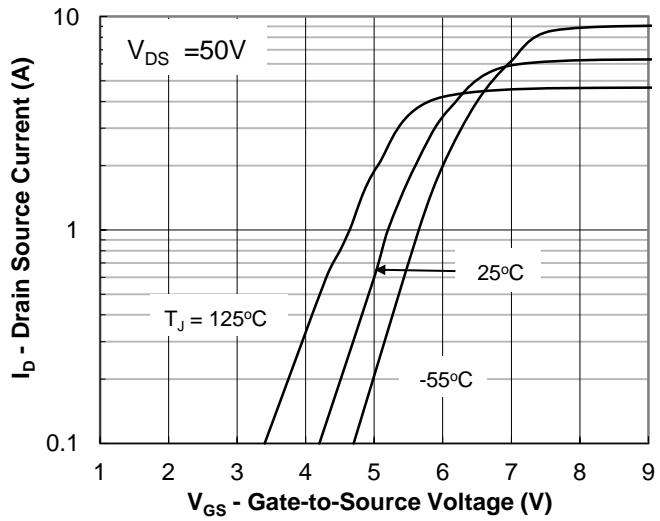


Fig.2 Transfer Characteristic

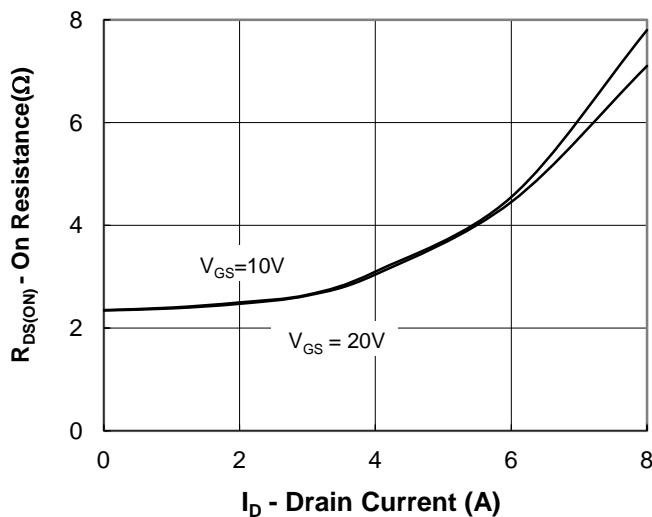


Fig.3 On-Resistance vs Drain Current

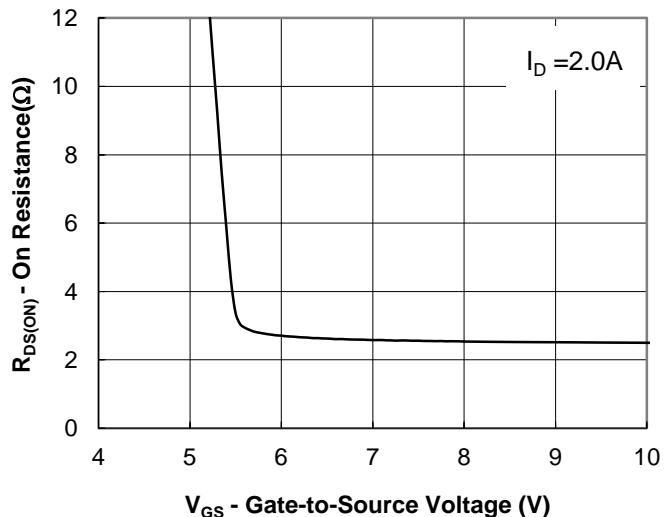


Fig.4 On-Resistance vs Gate to Source Voltage

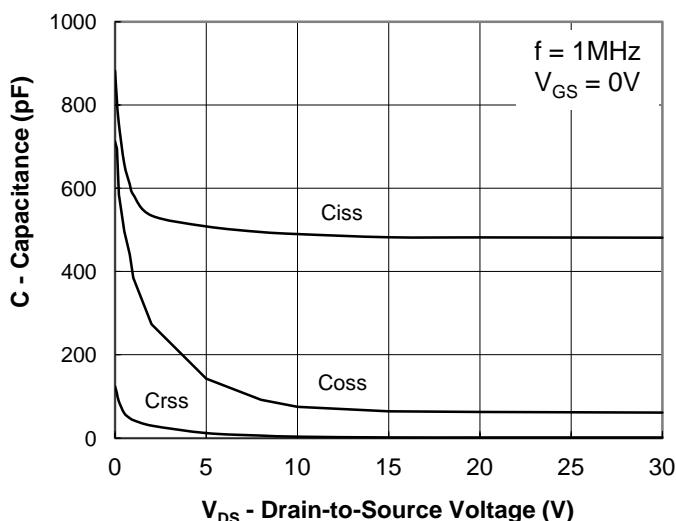


Fig.5 Capacitance Characteristic

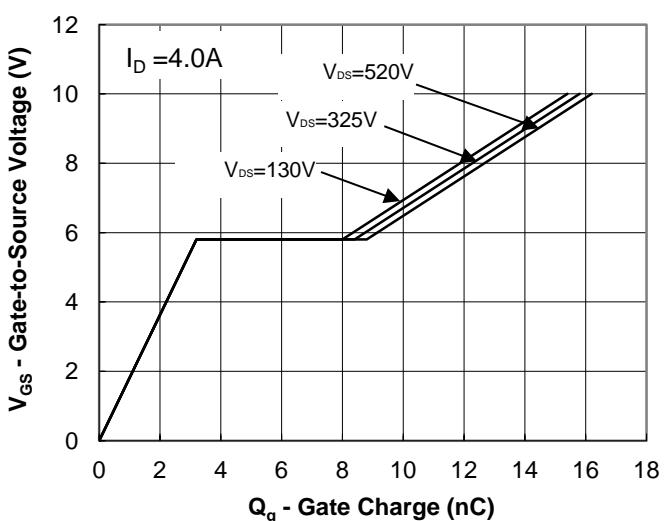
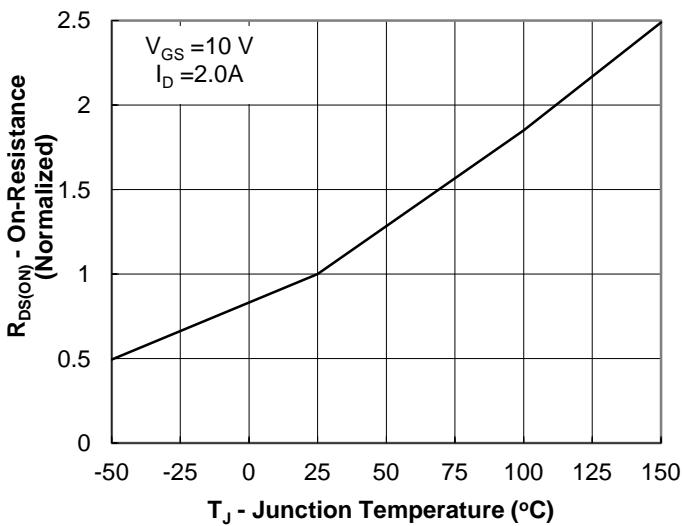
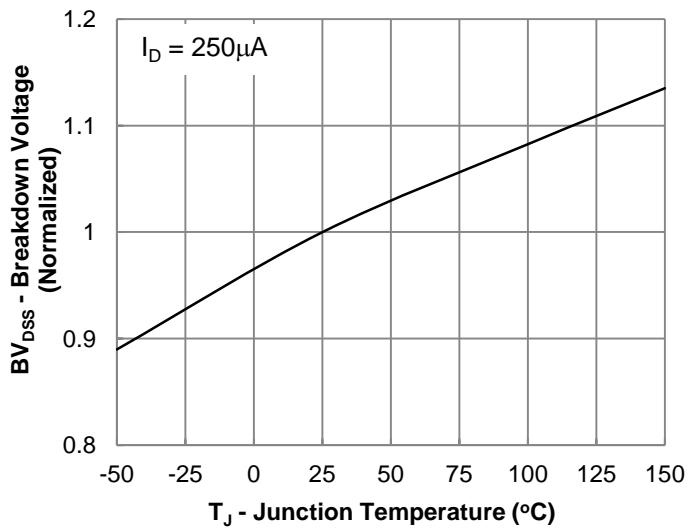
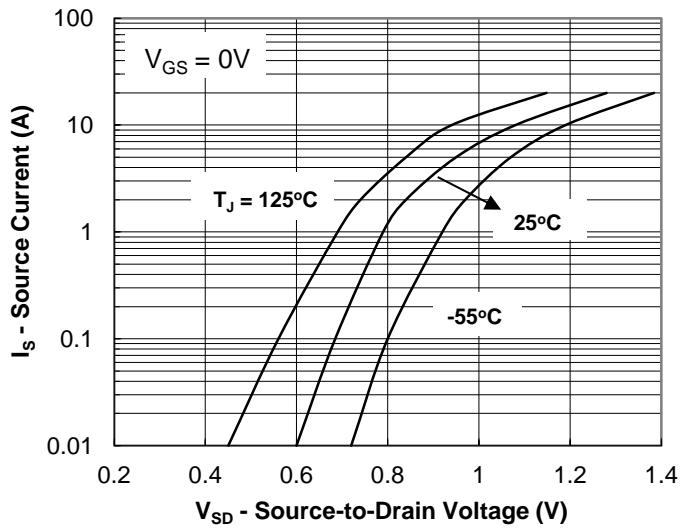


Fig.6 Gate Charge Characteristic

Typical Characteristics Curves ($T_C=25^\circ\text{C}$, unless otherwise noted)

Fig.7 On-Resistance vs Junction Temperature

Fig.8 Breakdown Voltage vs Junction Temperature

Fig.9 Body Diode Forward Voltage Characteristic